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Annotated Sheet Showing Changes

Mineo NOMOTO, et al.

Application No. 10/082,520

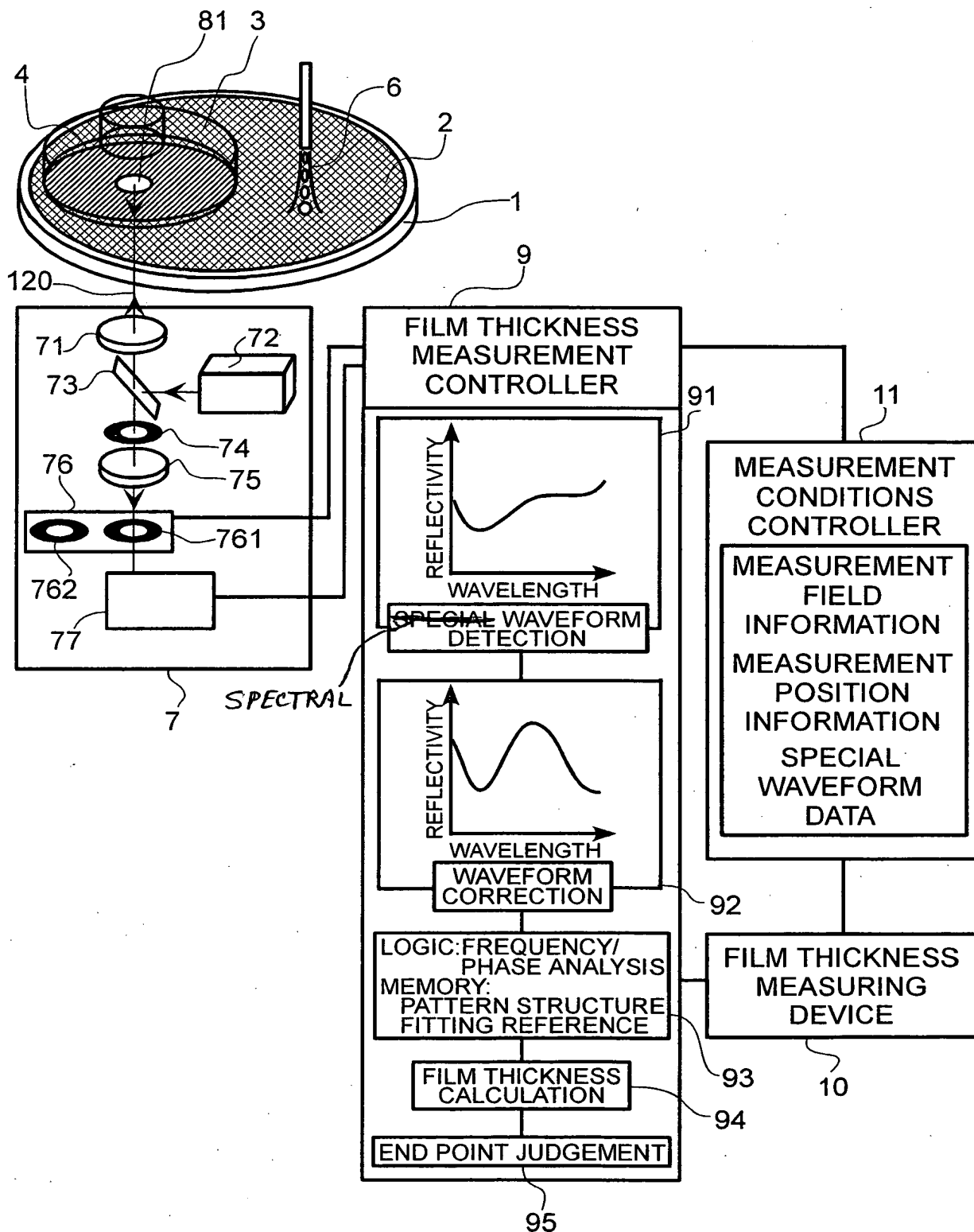
"Method and Apparatus for Measuring Thickness of Thin Film and Device Manufacturing Method Using Same"

Attorney Docket No. 16869P-041600US

Robert C. Colwell, Reg. No. 27,431

(650) 326-2400

FIG.2





Annotated Sheet Showing Changes

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FIG.13

